

**Notice of References Cited**

Application/Control No.

09/584,489

Applicant(s)/Patent Under  
Reexamination  
ANDRIESSEN ET AL.

Examiner

Kevin R Kruer

Art Unit

1773

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-3,617,320	11-1971	Lee, Sung Ki	106/1.25
	B	US-4,335,198	06-1982	Hanada et al.	346/135.1
	C	US-4,405,706	09-1983	Takahashi et al.	346/135.1
	D	US-4,388,400	06-1983	Tabei et al.	346/135.1
	E	US-6,187,508	02-2001	Andriessen et al.	430/273.1
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	58089397A	05-1983	Japan	Ricoh	--
	O	0875889A1	04-1998	EPO	Daems	--
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.